

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Application Number		10735123	
	Filing Date		2003-12-12	
	First Named Inventor	Igor KELLER		
	Art Unit	2128		
	Examiner Name	Russell Warren Frejd		
	Attorney Docket Number	8195.002.NPUS01		

U.S.PATENTS						
Examiner Initial*	Cite No	Patent Number	Kind Code ¹	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
/RF/	1	7065720	B2	2006-06-20	Croix	

If you wish to add additional U.S. Patent citation information please click the Add button.

U.S.PATENT APPLICATION PUBLICATIONS						
Examiner Initial*	Cite No	Publication Number	Kind Code ¹	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
	1					

If you wish to add additional U.S. Published Application citation information please click the Add button.

FOREIGN PATENT DOCUMENTS								
Examiner Initial*	Cite No	Foreign Document Number ³	Country Code ²	Kind Code ⁴	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear	T ⁵
	1							<input type="checkbox"/>

If you wish to add additional Foreign Patent Document citation information please click the Add button

NON-PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.	T ⁵

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number	10735123
Filing Date	2003-12-12
First Named Inventor	Igor KELLER
Art Unit	2128
Examiner Name	Russell Warren Frejd
Attorney Docket Number	8195.002.NPUS01

1		<input type="checkbox"/>
---	--	--------------------------

If you wish to add additional non-patent literature document citation information please click the Add button

EXAMINER SIGNATURE

Examiner Signature	/Russell Frejd/	Date Considered	09/27/2007
--------------------	-----------------	-----------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through a citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See Kind Codes of USPTO Patent Documents at www.USPTO.GOV or MPEP 901.04. ² Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁵ Applicant is to place a check mark here if English language translation is attached.

Form PTO-1449

Docket Number 188122000400

Application Number 10/735,123

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)

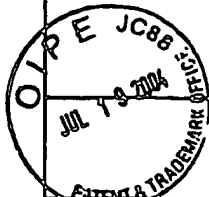
Applicant

10/735,123 Igor KELLER et al.

Filing Date December 12, 2003

Group Art Unit 2128

Mailing Date July 15, 2004



U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
RF	1.	R. Arunachalam et al., "TACO: Timing Analysis With COUpling", ACM 2000, 4 pgs.
	2.	P. Chen et al., "Miller Factor for Gate-Level Coupling Delay Calculation", IEEE, International Conference on Computer Aided Design, 2000, 7 pgs.
	3.	J. F. Croix et al., "Blade and Razor: Cell and Interconnect Delay Analysis Using Current-Based Models", DAC June 2-6, 2003, Anaheim CA, pp. 386-389.
	4.	F. Dartu et al., "Calculating Worst-Case Gate Delay Due to Dominant Capacitance Coupling", DAC 97, Anaheim CA, 6 pgs, 1997.
	5.	P. D. Gross et al., "Determination of Worst-Case Aggressor Alignment for Delay Calculation", ACM 1998, pgs. 212-219.
	6.	I. Keller et al., "A robust cell-level crosstalk delay change analysis", 8 pgs, NOVEMBER 2004.
	7.	I. Keller et al., "On a robust noise-on-delay cell-level analysis", 7 pgs, DATE UNAVAILABLE.
	8.	A. Odabasioglu et al., "PRIMA: Passive Reduced-Order Interconnect Macromodeling Algorithm", IEEE Transactions on Computer Aided Design of Integrated Circuits and Systems, vol. 17, no.8, Aug. 1998, pgs. 645-654.
	9.	V. Raghavan et al., "AWESpice: A General Tool for the Accurate and Efficient Simulation of Interconnect Problems", 29th ACM/IEEE Design Automation Conference, paper 6.3, 1992, pgs. 87-92.
	10.	K. Shepard, "Design Methodologies for Noise in Digital Integrated Circuits", 35th Design Automation Conference, ACM 1998, 6 pgs.
	11.	S. Sirichotiyakul et al., "Driver Modeling and Alignment for Worst-Case Delay Noise", IEEE Trans. on Very Large Scale Integration v. 11, no. 2, April 2003, 6 pgs.
RF	12.	V. Zolotov et al., "Noise Propagation and Failure Criteria for VLSI Designs", IEEE 2002, 8 pgs.

EXAMINER: /Russell Frejd/

DATE CONSIDERED: 07/17/2006

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

Form PTO-1449

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)

Docket Number 188122000400

Application Number 10/735,123

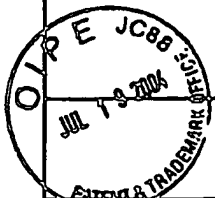
Applicant

Igor KELLER et al.

Filing Date December 12, 2003

Group Art Unit 2128

Mailing Date July 15, 2004



U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
RP	1.	R. Arunachalam et al., "TACO: Timing Analysis With Coupling", ACM 2000, 4 pgs.
	2.	P. Chen et al., "Miller Factor for Gate-Level Coupling Delay Calculation", IEEE, International Conference on Computer Aided Design, 2000, 7 pgs.
	3.	J. F. Croix et al., "Blade and Razor: Cell and Interconnect Delay Analysis Using Current-Based Models", DAC June 2-6, 2003, Anaheim CA, pp. 386-389.
	4.	F. Dartu et al., "Calculating Worst-Case Gate Delay Due to Dominant Capacitance Coupling", DAC 97, Anaheim CA, 6 pgs.
	5.	P. D. Gross et al., "Determination of Worst-Case Aggressor Alignment for Delay Calculation", ACM 1998, pgs. 212-219.
	6.	I. Keller et al., "A robust cell-level crosstalk delay change analysis", 8 pgs. <i>NO Date</i>
	7.	I. Keller et al., "On a robust noise-on-delay cell-level analysis", 7 pgs. <i>NO Date</i>
	8.	A. Odabasioglu et al., "PRIMA: Passive Reduced-Order Interconnect Macromodeling Algorithm", IEEE Transactions on Computer Aided Design of Integrated Circuits and Systems, vol. 17, no.8, Aug. 1998, pgs. 645-654.
	9.	V. Raghavan et al., "AWESpice: A General Tool for the Accurate and Efficient Simulation of Interconnect Problems", 29th ACM/IEEE Design Automation Conference, paper 6.3, 1992, pgs. 87-92.
	10.	K. Shepard, "Design Methodologies for Noise in Digital Integrated Circuits", 35th Design Automation Conference, ACM 1998, 6 pgs.
↓	11.	S. Sirichotiyakul et al., "Driver Modeling and Alignment for Worst-Case Delay Noise", IEEE Trans. on Very Large Scale Integration v. 11, no. 2, April 2003, 6 pgs.
RP	12.	V. Zolotov et al., "Noise Propagation and Failure Criteria for VLSI Designs", IEEE 2002, 8 pgs.

EXAMINER: /Russell Frejd/

DATE CONSIDERED: 07/17/2006

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.